

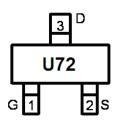
2N7002KU

Main Product Characteristics:

V _{DSS}	60V
R _{DS} (on)	3Ω(max.)
I _D	0.3A

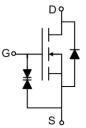


SOT-23



Marking and pin

Assignment



Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- ESD Rating: 2000V HBM
- 150°C operating temperature

Rojes Compliant

Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V①	0.3	٥
I _{DM}	Pulsed Drain Current2	1.2	A
P _D @TC = 25°C	Power Dissipation3	0.63	W
V _{DS}	Drain-Source Voltage	60	V
V _{GS}	Gate-to-Source Voltage	± 20	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{0JA}	Junction-to-ambient (t \leq 10s) ④		200	°C/W



Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	60	—	_	V	V _{GS} = 0V, ID = 250µA
D	Static Drain-to-Source on-resistance	—	1.6	3	Ω	V _{GS} =10V, I _D =0.5A
R _{DS(on)}		—	—	3.5	12	V _{GS} =5V, I _D =0.05A
$V_{\text{GS(th)}}$	Gate threshold voltage	1	—	2.5	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
I _{DSS}	Drain-to-Source leakage current		—	1	μA	$V_{\text{DS}} = 60 \text{V}, V_{\text{GS}} = 0 \text{V}$
	I _{GSS} Gate-to-Source forward leakage	_	—	±100	nA	$V_{GS}=\pm 5V, V_{DS}=0V$
IGSS		—	—	±10	uA	$V_{GS}=\pm 20V, V_{DS}=0V$
t _{d(on)}	Turn-on delay time	—	—	25	ns	V _{GS} =10V, VDS=30V,
$t_{d(off)}$	Turn-Off delay time	_		45	115	$ID=0.2A, R_{GEN}=10\Omega$
C _{iss}	Input capacitance	_	40	_		$V_{GS} = 0V$
Coss	Output capacitance	_	16.6	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	9.5	_		<i>f</i> = 1MHz

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

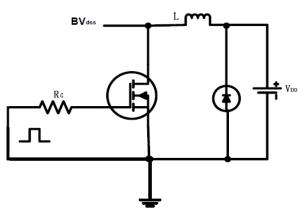
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current		Ι	0.3	A	MOSFET symbol
IS	(Body Diode)	_				showing the
I _{SM}	Pulsed Source Current		_	1.2	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	—		1.3	V	I _S =0.2A, V _{GS} =0V

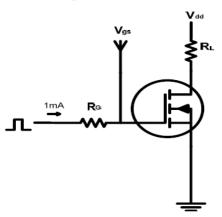


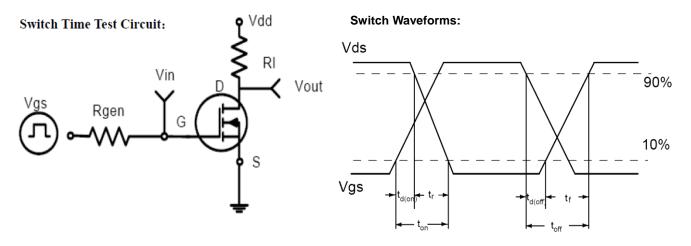
Test circuits and Waveforms

EAS test circuits:



Gate charge test circuit:



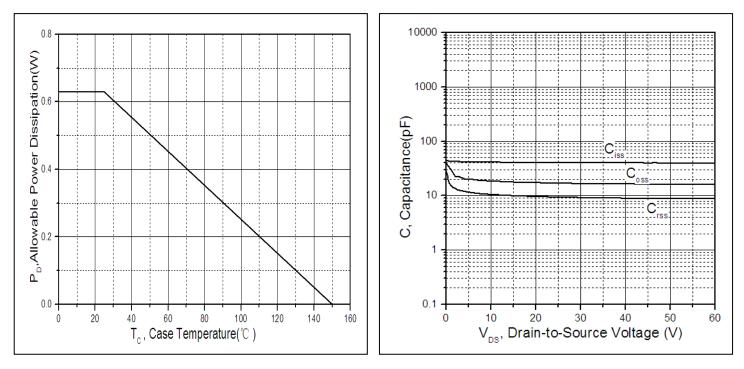


Notes:

- ①The maximum current rating is limited by bond-wires.
- 2 Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- (5) These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =150°C.



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Typical electrical and thermal characteristics

Figure 1. Power Dissipation Vs. Case Temperature

Figure 2.Typical Capacitance Vs. Drain-to-Source Voltage

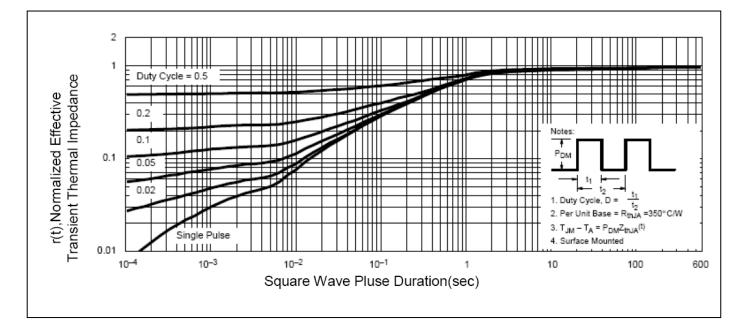
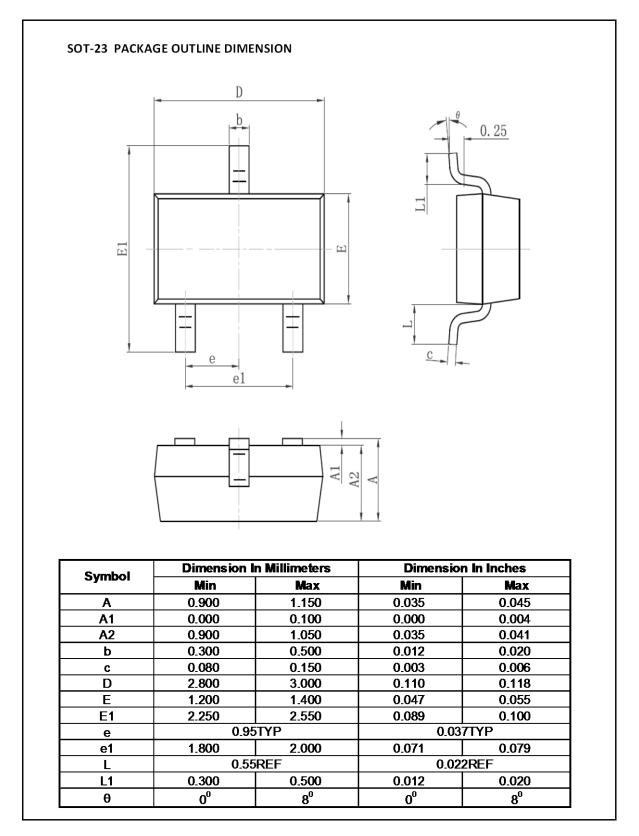


Figure3. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:





Ordering and Marking Information

Device Markin	g: U72	
	Package (Available)	
	SOT-23	
	Operating Temperature Range	
	C : -55 to 150 ℃	

Devices per Unit

Package Type	Units/ Tape	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/ Carton Box
				BUX	BUX
SOT-23	3000	10	30000	4	120000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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